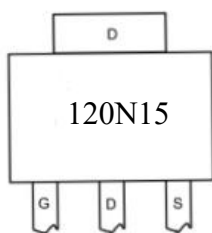


**Features**

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$

 B_{vds} **150V** **R_{dson}** **11mΩ** **I_D** **120A****Application**

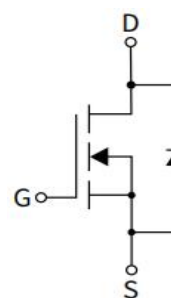
- DC-DC Converters
- Power management function
- Synchronous-rectification applications

RoHS**Package**

Marking and pin assignment



TO220 top view



Schematic diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
120N15	S120N15T	TO220	50

Absolute Maximum Ratings ($T_C=25^{\circ}\text{C}$ unless otherwise specified)

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	150	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current, $V_{GS}@10V^1$	$T_C=25^{\circ}\text{C}$	I_D	120	A
	$T_C=100^{\circ}\text{C}$		54	A
Pulsed Drain Current ²		I_{DM}	205	A
Single Pulsed Avalanche Energy ³		EAS	436	mJ
Avalanche Current		I_{AS}	-	A
Power Dissipation ⁴		P_D	56	W
Operating Junction Temperature Range		T_J	-55 ~ 150	$^{\circ}\text{C}$
Storage Temperature Range		T_{STG}	-55 ~ 150	$^{\circ}\text{C}$

Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient ¹	$R_{\theta JA}$	51	$^{\circ}\text{C/W}$
Thermal Resistance, Junction-to-Case ¹	$R_{\theta JC}$	1.2	$^{\circ}\text{C/W}$



Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HLS70N10T	TO220	1	2	3	Tube

Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain to Source Breakdown Voltage	V_{DS}	$I_D = 250\mu\text{A}, V_{GS}=0\text{V}$	150	-	-	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=150\text{V}, V_{GS}=0\text{V}, T_J=25^{\circ}\text{C}$	-	-	1	μA
		$V_{DS}=150\text{V}, V_{GS}=0\text{V}, T_J=100^{\circ}\text{C}$	-	-	100	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu\text{A}$	2.5	3.4	4.5	V
Static Drain-Source On-Resistance ²	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=1\text{A}$	-	11	12.5	m Ω
Gate Resistance	R_g	$V_{DS}=0\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$	-	1.6	-	Ω
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=75\text{V},$ $f=1\text{MHz}$	-	2049	-	pF
Output Capacitance	C_{oss}		-	247	-	
Reverse Transfer Capacitance	C_{rss}		-	12	-	
Total Gate Charge	Q_g	$V_{GS}=10\text{V}, V_{DS}=75\text{V},$ $I_D=20\text{A}$	-	28	-	nC
Gate Source Charge	Q_{gs}		-	9.4	-	
Gate Drain Charge	Q_{gd}		-	6.3	-	
Turn-ON Delay Time	$t_{d(on)}$	$V_{GS}=10\text{V}, V_{DD}=75\text{V},$ $I_D=20\text{A}, R_g=3\Omega$	-	4	-	ns
Rise Time	t_r		-	17	-	
Turn-OFF Delay Time	$t_{d(off)}$		-	18	-	
Fall Time	t_f		-	7.4	-	
Diode Forward Current ^{1,4}	I_S	$V_G=V_D=0\text{V}, \text{Force Current}$	-	-	120	A
Diode Forward Voltage ²	V_{SD}	$I_S=20\text{A}, V_{GS}=0\text{V}$	-	-	1.2	V
Reverse Recovery time	t_{rr}	$I_F=20\text{A}, di/dt=100\text{A}/\mu\text{s}$	-	102	-	ns
Reverse Recovery Charge	Q_{rr}		-	207	-	nC

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=150^{\circ}\text{C}$
2. The EAS data shows Max. rating . The test condition is $V_{DD}=75\text{V}, V_{GS}=10\text{V}, L=1\text{mH}$,
3. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.



Typical Performance Characteristics

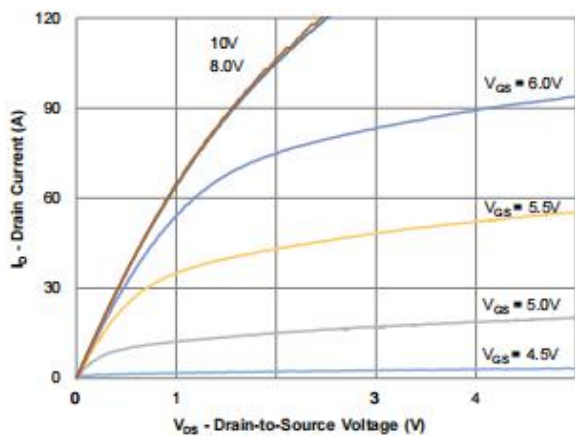


Figure 1: Output Characteristics

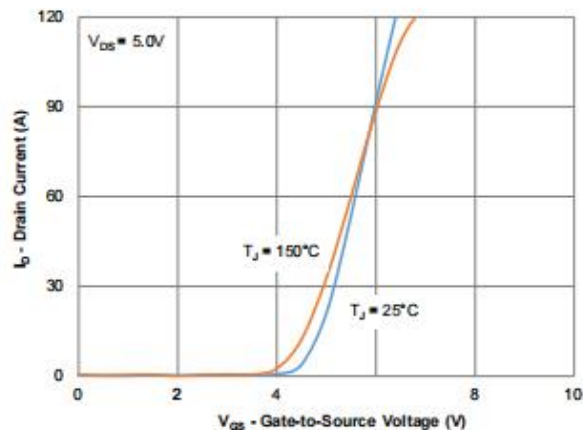


Figure 2: Transfer Characteristics

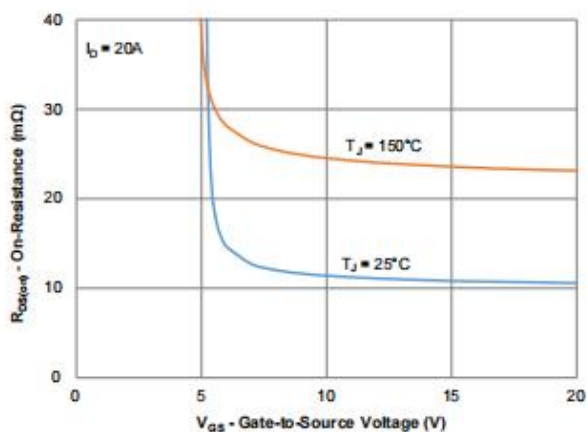


Figure 3: On-Resistance vs. Gate-Source Voltage

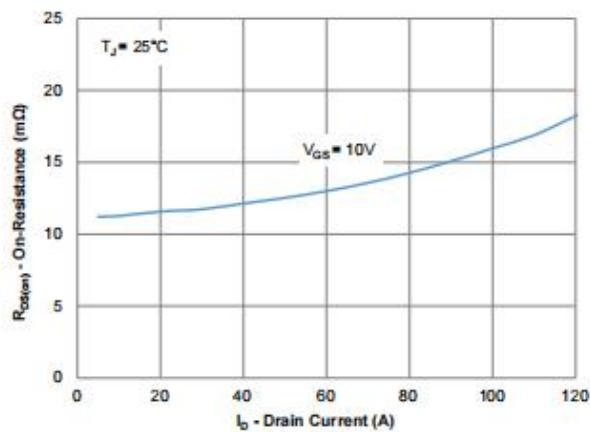


Figure 4: On-Resistance vs. Drain Current and Gate Voltage

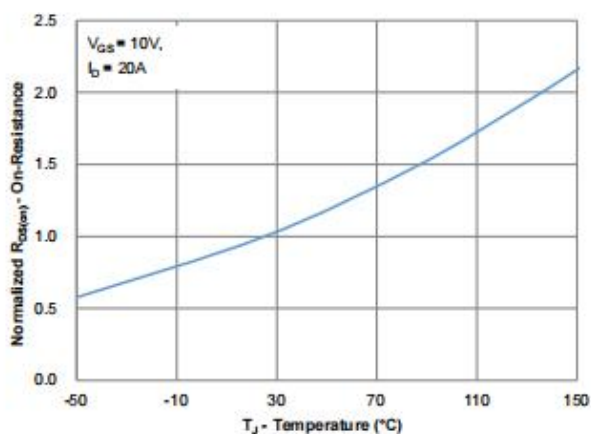


Figure 5: On-Resistance vs. Junction Temperature

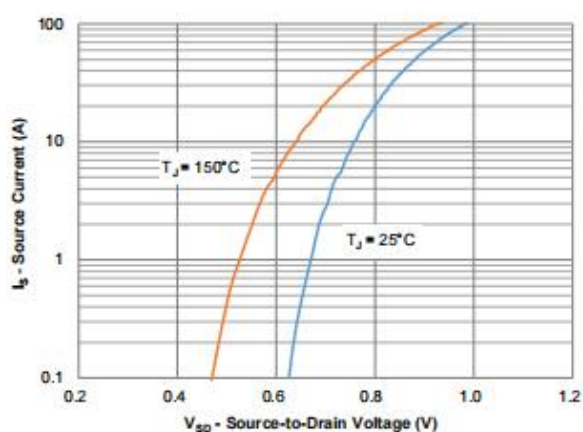


Figure 6: Source-Drain Diode Forward Voltage

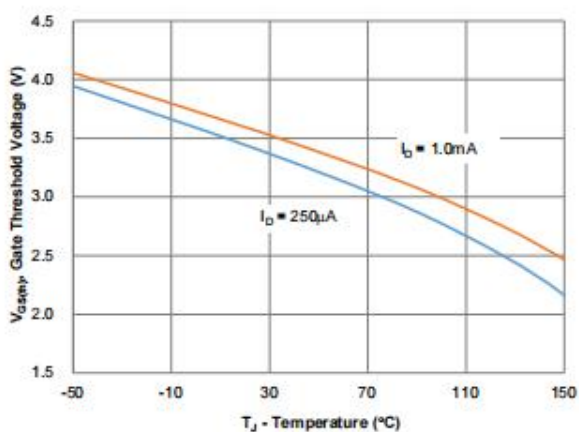


Figure 7: Gate Threshold Variation vs. Junction Temperature

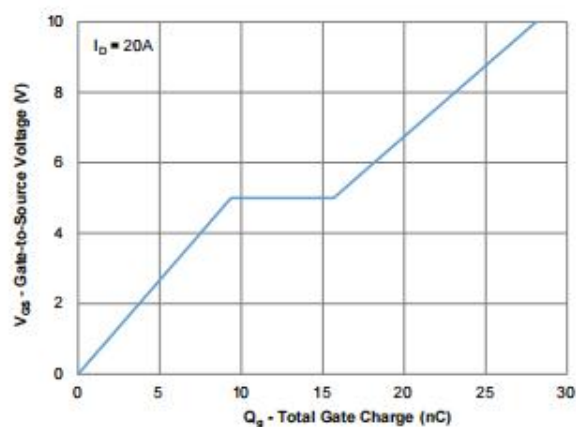


Figure 8: Gate Charge Characteristics

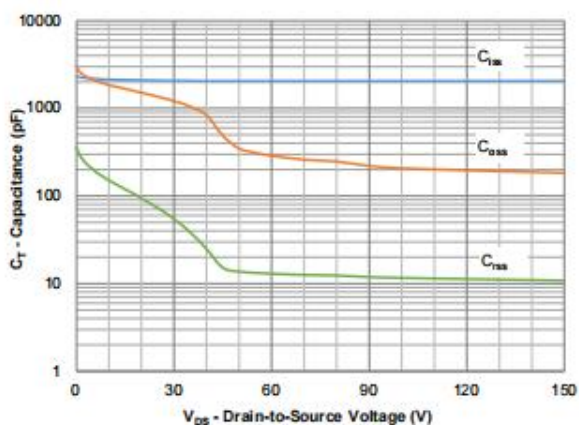


Figure 9: Capacitance Characteristics

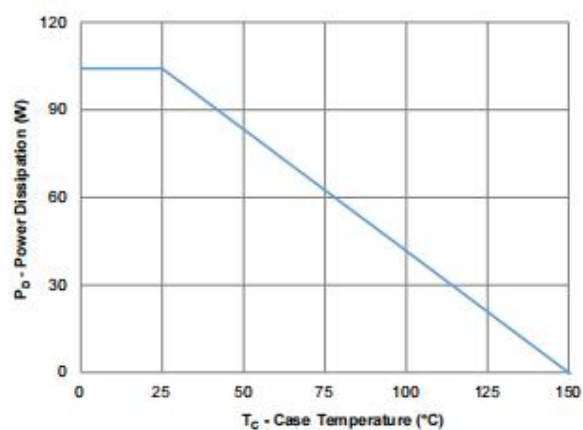


Figure 10: Power Derating

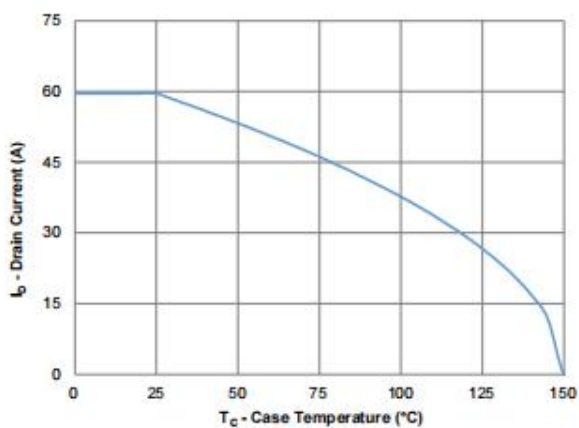


Figure 11: Current Derating

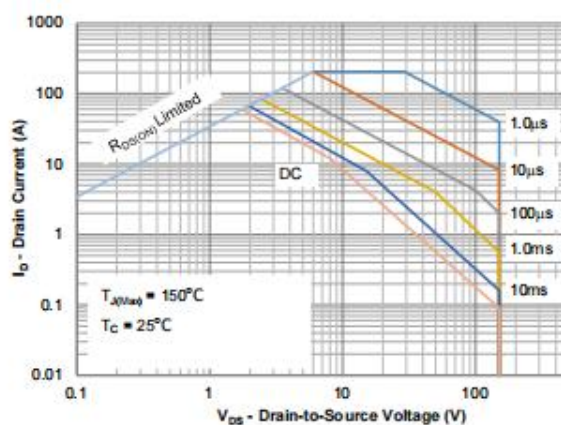


Figure 12: Safe Operating Area

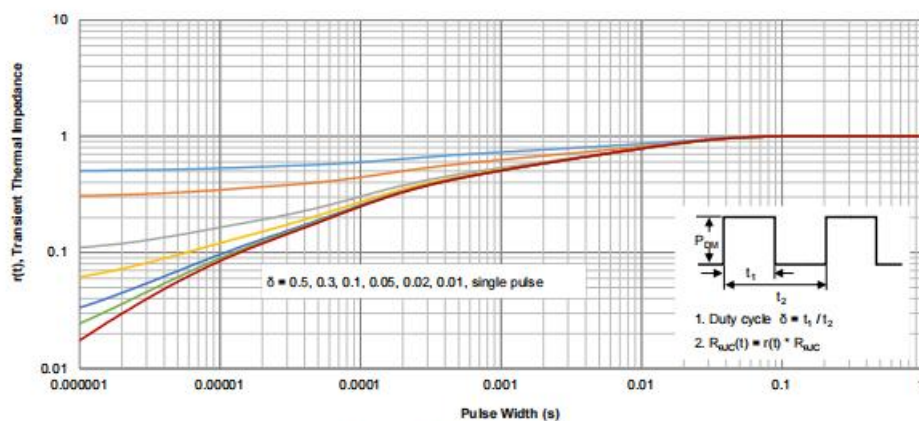
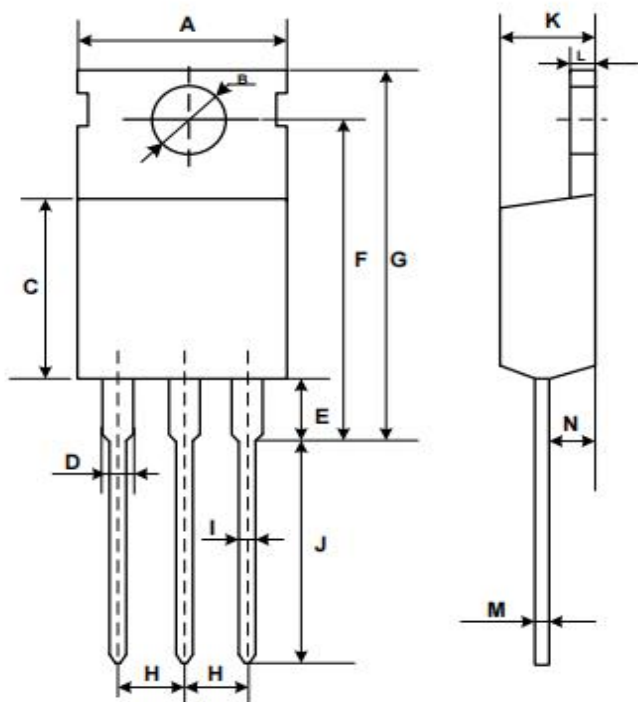


Figure 13: Normalized Maximum Transient Thermal Impedance

Package Dimensions TO220



SYMBOL	MM	
	MIN	MAX
A	9.70	10.30
B	3.40	3.80
C	8.80	9.40
D	1.17	1.47
E	2.60	3.50
F	15.10	16.70
G	19.55MAX	
H	2.54REF	
I	0.70	0.95
J	9.35	11.00
K	4.30	4.77
L	1.20	1.45
M	0.40	0.65
N	2.20	2.60



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Chip revision change

Date	Revision	Remarks